**PATENT** 

### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

				1		
IN RE	APPLICA	TION OF:	JACK ZEZHONG PENG	EXAMINER:		
APPLI	CATION I	No.:	TO BE ASSIGNED	ART UNIT:		
FILED			HEREWITH	Conf. No:		
	AND ME	MORY AF	EMICONDUCTOR MEMORY CELL RRAY USING A SINGLE D HAVING COUNTER-DOPED ED DIFFUSION WORDLINE			
			tion Disclosure Statement Wi on Filing or Before First Actio			
P.O. I	3ox 145	er for Pa 50 /A 22313		•		
Sir:						
1.	Timing	of Subr	mission			
	This information disclosure is being filed within three months of the filing date of this application or date of entry into the national stage of an international application or before the mailing date of a first Office action on the merits, whichever occurs last [37 C.F.R. § 1.97(b)]. The references listed on the enclosed Form PTO-1449 (modified) may be material to the examination of this application; the Examiner is requested to make them of record in the application.					
2.	Cited I	Informati	<u>on</u>			
	$\boxtimes$	Copies	of the following references are	enclosed:		
			All cited references References marked by asterisks The following: All Non-US Pater			
		Copies No.	of the following references can :	be found in parent U.S. Application		
		☐ F	All cited references References marked by asterisks The following:	S		

- This application was filed after 30 June 2003 and no copies of U.S. patents nor published applications are enclosed (See Notice of Deputy Commissioner Kunin on 11 July 2003).
- The following references are not in English. For each such reference, the undersigned has enclosed (i) a translation of the reference; (ii) a copy of a communication from a foreign patent office or International Searching Authority citing the reference, (iii) a copy of a reference which appears to be an English-language counterpart, or (iv) an English-language abstract for the reference prepared by a third party. Applicant has not verified that the translation, English-language counterpart or third-party abstract is an accurate representation of the teachings of the non-English reference, though, and reserves the right to demonstrate otherwise.

	All cited references
	References marked by ampersands
$\boxtimes$	The following: JP61292295

#### 3. Effect of Information Disclosure Statement (37 C.F.R. § 1.97(h))

This Information Disclosure Statement is not to be construed as a representation that: (i) a search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the cited information is, or is considered to be, material to patentability. In addition, applicant does not admit that any enclosed item of information constitutes prior art to the subject invention and specifically reserves the right to demonstrate that any such reference is not prior art.

#### 4. <u>Fee Payment</u>

No fees are believed due because this Information Disclosure Statement is being filed before the mailing date of the first Office Action.

	· ·
	cant further submits that no fee is due in light of the following cation under 37 C.F.R. § 1.97(e) (check only one):
	In accordance with 37 C.F.R. § 1.97(e)(1), the undersigned hereby states that each item of information submitted herewith was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement; or
	In accordance with 37 C.F.R. § 1.97(e)(2), the undersigned hereby states that no item of information submitted herewith was cited in a communication from a foreign patent office in a counterpart foreign application, or, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any

individual designated in 37 C.F.R. § 1.56(c), more than three months prior to the filing of this statement.

However, should the Commissioner determine that fees are due in order for this Information Disclosure Statement to be considered, the Commissioner is hereby authorized to charge such fees to Deposit Account No. 50-0665.

#### 5. Patent Term Adjustment (37 C.F.R. § 1.704(d))

The undersigned states that each item of information submitted herewith was cited in a communication from a foreign patent office in a counterpart application and that this communication was not received by any individual designated in 37 C.F.R. § 1.56(c) more than thirty days prior to the filing of this statement. 37 C.F.R. § 1.704(d).

Respectfully submitted, Perkins Coie LLP

Chun M. Ng

Registration No. 36,878

Correspondence Address:

Customer No. 25096 Perkins Coie LLP P.O. Box 1247 Seattle, Washington 98111-1247 (206) 359-8000

Form PTO-1449 (Modified) (Use several sheets if necessary)

COMPLETE IF KNOWN					
Application Number					
Confirmation Number					
Filing Date					
First Named Inventor	Jack Zezhong Peng				
Group Art Unit					
Examiner Name					
Attorney Docket No.	384848014US				

Sheet	1	of	4
0.11001		•	•

			U.S. PATENT DOCUMENTS		
Examiner Initials*	Cite No.	U.S. Patent or Application  Kind Code  NUMBER (if known)	Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		3,634,929	Yoshida et al.	01/18/72	
		4,322,822	McPherson	03/30/82	
		4,488,262	Basire et al.	12/11/84	
		4,490,900	Chiu	01/01/85	
		4,502,208	McPherson	03/05/85	
		4,507,757	McElroy	03/26/85	
		4,543,594	Mohsen et al.	09/24/85	
		4,546,273	Osman	10/08/85	
		4,599,705	Holmberg, et al.	07/08/86	
		4,613,886	Chwang	09/23/86	~
	-	4,677,742	Johnson	07/07/87	***
		4,758,986	Kuo	07/19/88	
<del></del> .		4,794,562	Kato et al.	12/27/88	
		4,823,181	Mohsen et al.	04/18/89	
		4,876,220	Mohsen et al.	10/24/89	
		4,899,205	Hamdy et al.	02/06/90	
		4,943,538	Mohsen et al.	07/24/90	***************************************
		4,962,342	Mead et al.	10/09/90	
		5,138,410	Takebuchi	08/11/92	
		5,150,179	Gill	09/22/92	
		5,303,185	Hazani	04/12/94	
		5,304,871	Dharmarajan et al.	04/19/94	
		5,323,342	Wada et al.	06/21/94	
		5,412,244	Hamdy et al.	05/02/95,	
		5,477,499	Van Buskirk et al.	12/19/95	
<del></del>		5,496,756	Sharma et al.	03/05/96	
		5,576,568	Kowshik	11/19/96	
		5,578,848	Kwong et al.	11/26/96	

EXAMINER		DATE CONSIDERED	
		<u> </u>	
*EXAMINER:	Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application(s).		

Form PTO-1449 (Modified) (Use several sheets if necessary)

COMPLETE IF KNOWN					
Jack Zezhong Peng					
384848014US					
	Jack Zezhong Peng				

Sheet	2	of	4
Ollect		OI .	7

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No.	U.S. Patent or	Application  Kind Code (if known)	Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		5,586,270		Rotier et al.	12/17/96	
		5,587,603		Kowshik	12/24/96	
		5,600,265		El Gamal et al.	02/04/97	
		5,675,541		Leterrier	10/07/97	
		5,675,547		Koga	10/07/97	
		5,745,417		Kobayashi et al.	04/28/98	
		5,825,200		Kolze	10/20/98	
		5,825,201		Kolze	10/20/98	
		5,880,512		Gordon et al.	03/09/99	
		5,909,049		McCollum	06/01/99	
		5,986,931		Caywood	11//1699	
		5,986,939		Yamada	11/16/99	
		6,016,268		Worley	01/18/00	
		6,034,893		Mehta	03/07/00	
		6,040,968		Duvvury et al.	03/21/00	
		6,064,595		Logie et al.	05/16/00	
		6,084,428		Kolze et al.	07/04/00	
		6,097,077		Gordon et al.	08/01/00	
		6,157,568		Schmidt	12/05/00	
		6,166,954		Chern	12/26/00	
		6,214,666		Mehta	04/10/01	
		6,215,140		Reisinger et al.	04/10/01	
		6,218,274		Komatsu	04/17/01	
		6,232,631		Schmidt et al.	05/15/01	
		6,249,809		Bro	06/19/01	
		6,282,123		Mehta	08/28/01	
		6,294,809		Logie	09/25/01	
		6,297,103		Ahn et al.	10/02/01	

EXAMINER		DATE CONSIDERED -	_	
*EXAMINER:	Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not			
	considered. Include copy of this form with next communication to application(s).			

Form PTO-1449 (Modified) (Use several sheets if necessary)

of

4

3

Sheet

\*EXAMINER:

COMPLETE IF KNOWN					
Application Number		_			
Confirmation Number					
Filing Date					
First Named Inventor	Jack Zezhong Peng				
Group Art Unit					
Examiner Name					
Attorney Docket No.	384848014US				

**U.S. PATENT DOCUMENTS** Date of U.S. Patent or Application Publication or Filing Date Pages, Columns, Lines, Examiner Cite Kind Code Name of Patentee or Inventor of Cited Where Relevant Passages or Relevant Figures Appear Initials\* NUMBER (if known) of Cited Document Document No. 6.304.666 Warren et al. 10/16/01 6,351,428 **Forbes** 02/26/02 Candelier et al. 6.421.293 07/16/02 6,431,456 Nishizawa et al. 08/13/02 6,456,535 Forbes et al. 09/24/02 6,556,481 Hsu et al. 04/29/03 US2001/0003374 Bohmer et al. 06/14/01 **FOREIGN PATENT DOCUMENTS** Date of Foreign Patent or Application Publication or Pages, Columns, Lines, Filing Date Where Relevant Examiner Cite Kind Code Name of Patentee or Applicant of Cited Passages or Relevant (if known) Initials\* No. Office NUMBER of Cited Document Document Т Figures Appear EP 0 295 935 Advanced Micro Devices, Inc. 12/21/88 JP 61292295 Fujitsu Ltd. 12/23/86 OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item Examiner Cite (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city Initials\* No. and/or country where published Т MIRANDA, ENRIQUE et al; Analytic Modeling of Leakage Current Through Multiple Breakdown Paths in SiO2 Films, 39<sup>th</sup> Annual International Reliability Physics Symposium; Orlando, FL 2001. LOMBARDO, S. et al; Softening of Breakdown in Ultra-Thin Gate Oxide nMOSFET's at Low Inversion Layer Density; 39th Annual International Reliability Physics Symposium; Orlando, FL 2001. WU, E.W. et al; Voltage-Dependent Voltage-Acceleration of Oxide Breakdown for Ultra-Thin Oxides; IEEE, 2000. RASRAS, MAHMOUD et al; Substrate Hole Current Origin After Oxide Breakdown; IEEE, 2000. **EXAMINER** DATE CONSIDERED

Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not

considered. Include copy of this form with next communication to application(s).

Form PTO-1449 (Modified) (Use several sheets if necessary)

of

4

Sheet

COMPLETE IF KNOWN				
Application Number				
Confirmation Number				
Filing Date				
First Named Inventor	Jack Zezhong Peng			
Group Art Unit				
Examiner Name				
Attorney Docket No.	384848014US			

OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city and/or country where published.	Т	
		SUNE, JORDI et al; Post Soft Breakdown Conduction in SiO2 Gate Oxides; IEEE, 2000.		
		DeGRAAF, C., et al, A Novel High-Density Low-Cost Diode Programmable Read Only Memory, IEEE, 1996.		
		·		

4

EXAMINER		DATE CONSIDERED	
*EXAMINER:	Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not		
	considered. Include copy of this form with next communication to application(s).		